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| Notice of References Cited | Application/Control No. 10/699,321 | Applicant(s)/Patent Under Reexamination LOGIE, STEWART | |
| | Examiner Jesse A. Fenty | Art Unit 2815 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------|----------------|
| | A | US-5,276,346 | 01-1994 | Iwai et al. | 257/360 |
| | B | US-5,270,565 | 12-1993 | Lee et al. | 257/358 |
| | C | US-2003/0173630 A1 | 09-2003 | Lin et al. | 257/406 |
| | D | US-2003/0213971 A1 | 11-2003 | Yu, Ta-Lee | 257/119 |
| | E | US-2003/0201498 A1 | 10-2003 | Hu et al. | 257/355 |
| | F | US-2003/0222273 A1 | 12-2003 | Kunz et al. | 257/119 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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